

APPRAISER : DNN fault resilience analysis employing approximation errors

Taheri, Mahdi; Ahmadilivani, Mohammad Hasan; Jenihhin, Maksim; Daneshtalab, Masoud; Raik, Jaan 2023 26th International Symposium on Design and Diagnostics of Electronic Circuits and Systems (DDECS) 2023 / p. 124–127 : ill
<https://ddecs2023.taltech.ee/> <https://doi.org/10.1109/DDECS57882.2023.10139468>

Parallel pseudo-exhaustive testing of array multipliers with data-controlled segmentation

Oyeniran, Adeboye Stephen; Azad, Siavoosh Payandeh; Ubar, Raimund-Johannes 2018 IEEE International Symposium on Circuits and Systems (ISCAS) : 27-30 May 2018, Florence, Italy : proceedings 2018 / 5 p.: ill
<https://doi.org/10.1109/ISCAS.2018.8350936> [Conference proceedings at Scopus](#) [Article at Scopus](#) [Article at WOS](#)